Benchtop EDXRF Elemental Analyzer

test method

For the determination of total sulfur in petroleum and petroleum products that are single-phase. These materials can include diesel fuel, jet fuel, kerosene, other distillate oil, naphtha, residual oil, lubricating base oil, hydraulic oil, crude oil, unleaded gasoline, gasohol, and similar petroleum products. Also, for the determination of the total lead content of a gasoline.

EDX2000 elemental analyzer

The K47910 EDXRF can analyze a large array of elements from 11Na to 92U in solids, liquids, alloys, powders and thin films. The Plus model features a Silicon Drift Detector which delivers exceptional short-term repeatability and long-term reproducibility with excellent element peak resolution. Also, the K47901 features a modern smartphone style "icon-driven" user interface and built-in thermal printer. Network connections enable LIMS connectivity.

Software

- Qualitative and Quantitative Analysis
- Normalization and Validation Feature
- Fundamental Parameters
- Data Export Function with LIMS compatibility
- User Selectable Shaping Times
- · Simple Flow Bar Wizard to create new applications
- Icon Driven Graphical User Interface
- Password Protection

Dimensions wxdxh,in.(cm) 13 x 17 x 14.8 (33.1 x 43.2 x 37.6) Net Weight: 35 lbs (16 kg)

Electrical Requirements

100/240V, 1.4A, 50/60Hz Single Phase AC

ordering information

catalog no. description

K47910 EDX2000 Benchtop EDXRF Elemental Analyzer 100/240V

accessories

K47900-16 Position 32 mm Automatic Sample ChangerK47900-25 Position 40 mm Automatic Sample ChangerK47900-3Helium Purge OptionK47900-42-Stage Helium Regulator



K47910 EDX2000 Benchtop EDXRF Elemental Analyzer

specifications

Conforms to the specifications of: ASTM D4294, D5059, D6481, ISO 20847, ISO 8754, IP 496, IP 336, JIS K 2541-1 Excitation: 50 kV X-Ray Tube 4W Maximum Power 6 Tube Filter Positions with Optics Spill/Contamination Protection Detection: High Performance Silicon Drift Semiconductor Detector Peltier Thermo-Electric Cooling High Spectral Resolution and Count Rate Sample Chamber: Large 190 x 165 x 60 mm sample chamber Single Position 32 mm sample aperture Single Position 40 mm sample aperture **Bulk Sample Aperture** User Interface: 8" WVGA Touch Screen Interface **Embedded Computer** Internal Thermal Printer **USB & Ethernet Connections Environmental Conditions:** Ambient Temperatures 10 - 35°C (50 - 95°F) Relative Humidity < 85% non-condensing Vibration undetectable by human Free from corrosive gas, dust, and particles



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